

L-Band Avionics Transistor

The high power pulsed avionics transistor part number IB1012S20 is designed for L-Band avionics systems operating at 1025 to 1150 MHz. While operating in class C mode under DME pulse conditions at $V_{CC}=50V$, this common base device supplies a minimum of 20 watts of peak pulse power. It utilizes a low loss internal input impedance matching structure to yield maximum device gain and to ease the implementation of external matching circuitry. The new generation bipolar transistor geometry utilizes a gold metallization system to achieve maximum reliability. Emitter ballast resistance is incorporated on the active cell for optimum thermal distribution and maximum reliability. All devices are 100% screened for large signal RF parameters.



Silicon Bipolar

- Ultra-high f_T

Class C Operation

- High Efficiency

Common Base Configuration

- Single Power Supply

Gold Metal

- Maximum Reliability

Emitter Ballasting

- Optimum Thermal Distribution

Internal Impedance Matching

- Ease of Use
- Ultra-low Loss Design

Be0 Package

- Unmatched Thermal Reliability

RF Test Fixture

- Broadband
- Matched to 50Ω
- Long-term Correlation
- 100% Device RF Screening
- No External Tuning Allowed
- Micro-strip structure on soft pc board with dielectric constant 10.5

TYPICAL DATA TYPICAL DATA TYPICAL DATA TYPICAL DATA

General Information	Test Sequence Name	Freq (MHz)	Pin (W)	RL (dB)	POUT (W)	GP (dB)	dG (dB)	IC (A)	nc (%)	Droop (dB)	VSWR-S 1.5:1 (P-F)	VSWR-LMT 3:1 (P-F)
IB1012S20												
Date: 3/31/2009												
Assbly Lot - SN : D4001-1	Nominal	1025	1.6	-15.0	22.6	11.50		1.000	45.2	0.08	P	P
Wafer : BV15E-3-5												
Test Fixture : 2371	Nominal	1090	1.6	-14.0	24.4	11.83	0.52	1.000	48.8	0.07	P	P
Pass / Fail : Device Passes												
OPERATOR: FB	Nominal	1150	1.6	-14.0	25.5	12.02		1.100	46.4	0.07	P	P
Vcc=50V Pulse: 10us-1%												

MAXIMUM RATINGS

Screen	Parameter	Symbol	Min	Max	Units	Test Conditions
BD	Collector-Emitter Voltage	V_{CES}	--	85	V	--
BD	Emitter-Base Voltage	V_{EBO}	--	2	V	--
BD	Storage Temperature Range	T_{STG}	-55	+150	°C	--
BD	Operating Junction Temperature Range	T_J	-55	+200	°C	--
Note	Screen 'BD' = parameter qualified By Design.					

THERMAL CHARACTERISTICS

Screen	Parameter	Symbol	Min	Max	Units	Test Conditions
BD	Thermal Resistance	$R_{TH(JC)}$	--	TBD	°C/W	$V_{CC}=50V$, Pulse format= DME (10 μ s, 1%), $T_F=25\pm 5^\circ C$, $P_{IN}=1.6W$, $N_C=40\%$
Note	Screen 'BD' = parameter qualified By Design.					

PROCESSING SPECIFICATIONS

Screen	Parameter	Symbol	Min	Max	Units	Test Conditions
100%	DC Wafer Probe	--	--	--	--	Per Integra specification.
Q1	Wafer DC and RF Qualification	--	--	--	--	Per Integra specification.
LM	Wire Bond Strength	--	--	--	--	Line monitor per Integra specification.
100%	Pre-cap visual inspection	--	--	--	--	Per Integra specification
100%	Gross leak test	--	--	--	--	MIL-STD-750D, Method 1071, Test Condition C
Note	Screen 'Q1' = parameter is qualified by assembly and test of 3 pieces minimum per wafer.					
Note	Screen 'LM' = parameter is qualified by assembly line monitor.					

DC ELECTRICAL CHARACTERISTICS

Screen	Parameter	Symbol	Min	Max	Units	Test Conditions
100%	Collector-Emitter Breakdown Voltage	BV_{CES}	85	--	V	$I_C = 10mA$, $V_{BE} = 0V$, $T_F = 25\pm 5^\circ C$.
100%	Zero Base Voltage Collector Leakage Current	I_{CES}	--	100	μA	$V_{CE} = 50V$, $V_{BE} = 0V$, $T_F = 25\pm 5^\circ C$.
100%	DC Current Gain	H_{FE}	10	100	--	$V_{CE} = 5V$, $I_C = 0.1A$, $T_F = 25\pm 5^\circ C$.

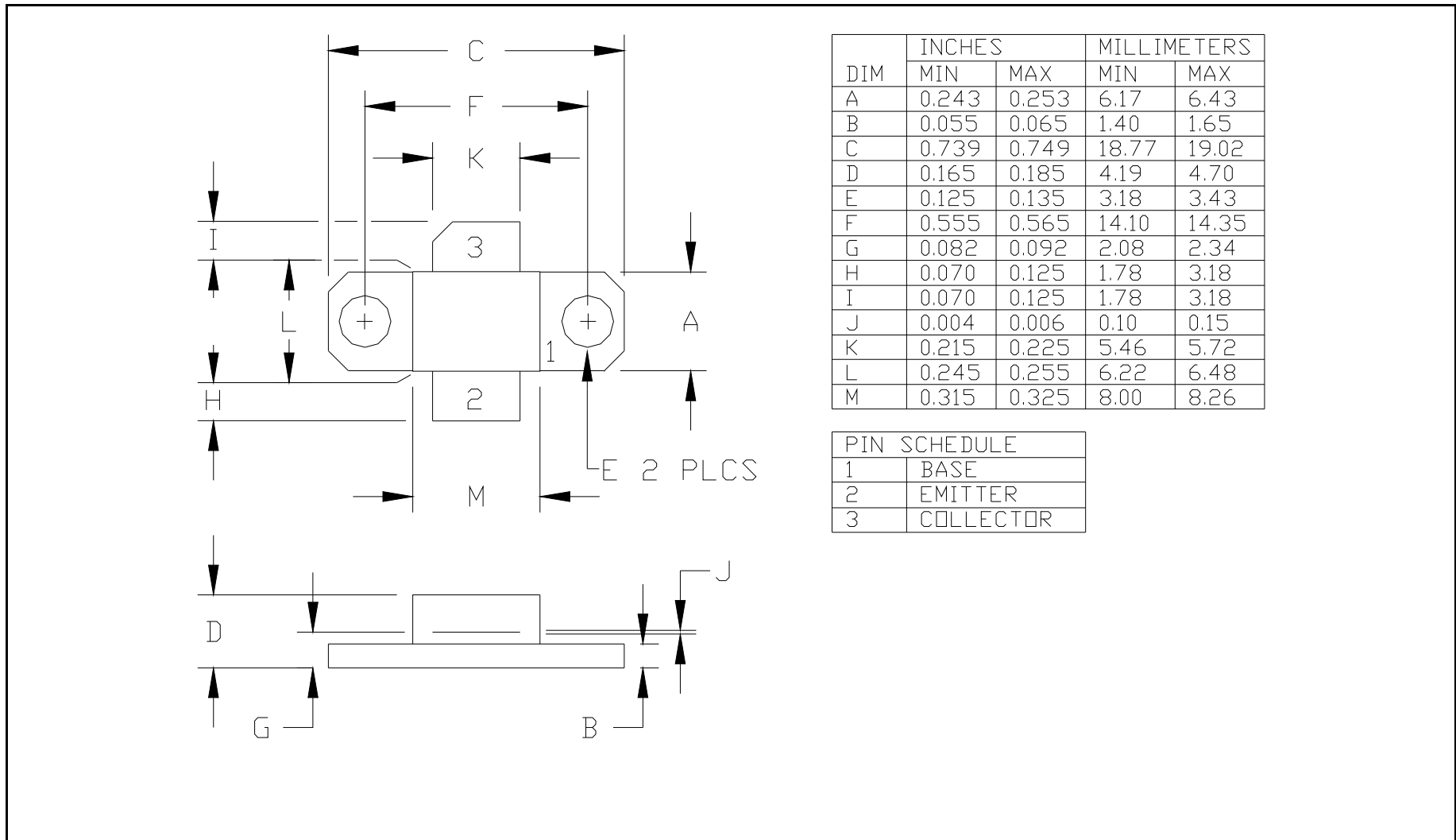
RF ELECTRICAL CHARACTERISTICS

Screen	Parameter	Symbol	Min	Max	Units	Test Conditions
100%	Input Return Loss	IRL	-18	-10	dB	$V_{CC}=50V$, $P_{IN}=1.6W$, Pulse = Note 2, $T_F=25\pm5^\circ C$, $F=F1$.
BD	Maximum Overdrive	$P_{IN(MAX)}$	--	2.15	W	$V_{CC}=50V$, Pulse = Note 2, $T_F=25\pm5^\circ C$, $F=F1$.
100%	Power Gain	G_P	11.0	12.5	dB	$V_{CC}=50V$, $P_{IN}=1.6W$, Pulse = Note 2, $T_F=25\pm5^\circ C$, $F=F1$
100%	Gain Flatness	dG	--	1.5	dB	$V_{CC}=50V$, $P_{IN}=1.6W$, Pulse = Note 2, $T_F=25\pm5^\circ C$, $F=F1$
100%	Output Power	P_{out}	20.0	28.5	W	$V_{CC}=50V$, $P_{IN}=1.6W$, Pulse = Note 2, $T_F=25\pm5^\circ C$, $F=F1$
100%	Collector Efficiency ($P_O/I_C/V_{CC}$)	N_C	40	75	%	$V_{CC}=50V$, $P_{IN}=1.6W$, Pulse = Note 2, $T_F=25\pm5^\circ C$, $F=F1$.
100%	Pulse Amplitude Droop	Droop	-0.5	0.5	dB	$V_{CC}=50V$, $P_{IN}=1.6W$, Pulse = Note 2, $T_F=25\pm5^\circ C$, $F=F1$.
100%	Stability into 1.5:1 VSWR	VSWR-S	--	--	--	$V_{CC}=50V$, $P_{IN}=1.6W$, Pulse = Note 2, $T_F=25\pm5^\circ C$, $F=F1$. Rotate 1.5:1 output VSWR through 360° phase. No oscillatory or pulse break-up characteristics allowed on detected output pulse.
100%	Load Mismatch Tolerance	VSWR-LMT	3:1	--	--	$V_{CC}=50V$, $P_{IN}=1.6W$, Pulse = Note 2, $T_F=25\pm5^\circ C$, $F=F1$. Rotate 3:1 output VSWR through 360° phase. Survival.
BD	Pulse Risetime	RT	--	80	ns	$V_{CC}=50V$, $P_{IN}=1.6W$, Pulse = Note 2, $T_F=25\pm5^\circ C$, $F=F1$. Measure between 10% and 90% detected power points.
Note 1	F1 = 1025/1090/1150 MHz.					
Note 2	Pulse format = DME (10µs, 1%)					
Note 3	T_F = Device flange temperature.					
Note 4	Screen 'BD' = parameter qualified By Design.					

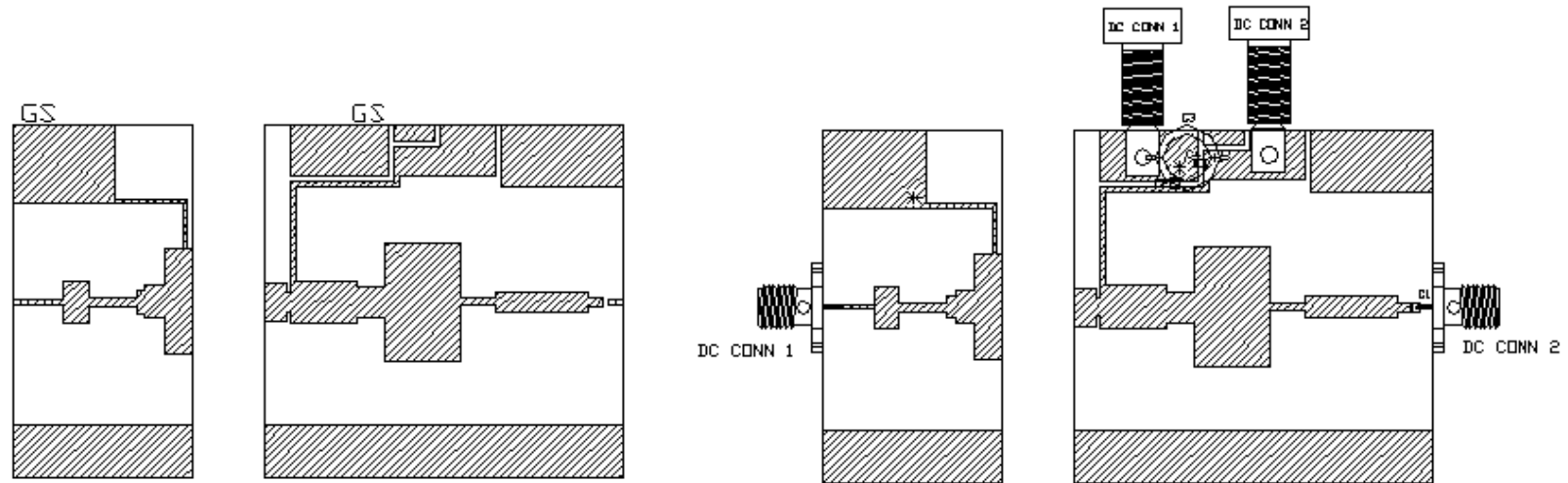
RF TEST FIXTURE IMPEDANCE CHARACTERISTICS

Frequency (MHz)	Z_{IF} (Ω)	Z_{OF} (Ω)
1025	5.30 -j4.87	7.53 + j11.2
1090	5.39 -j4.16	8.84 + j11.3
1150	5.68 -j3.61	9.38 + j11.78
Impedance Definition		

PACKAGE DIMENSIONAL OUTLINE DRAWING



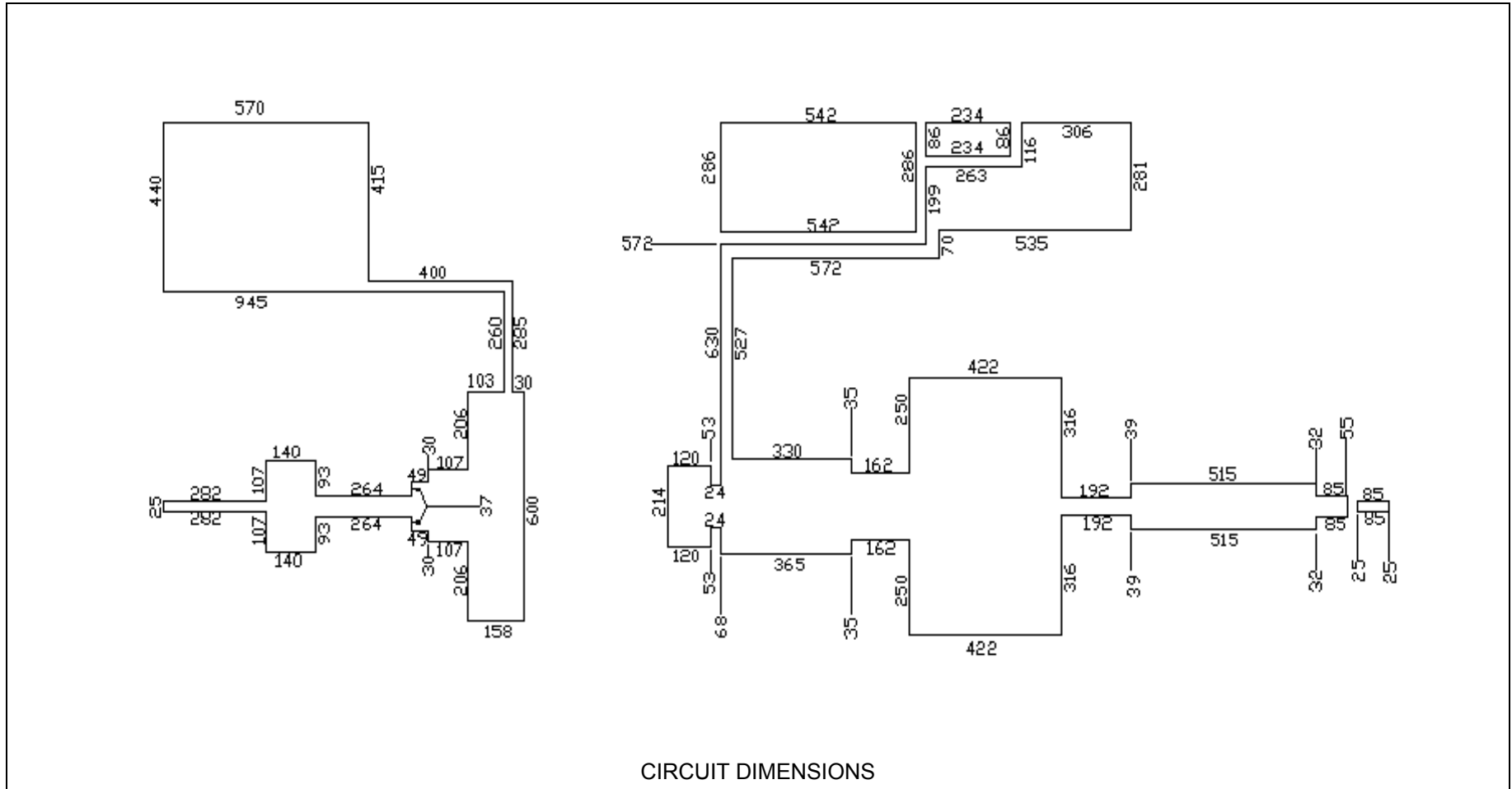
RF TEST FIXTURE

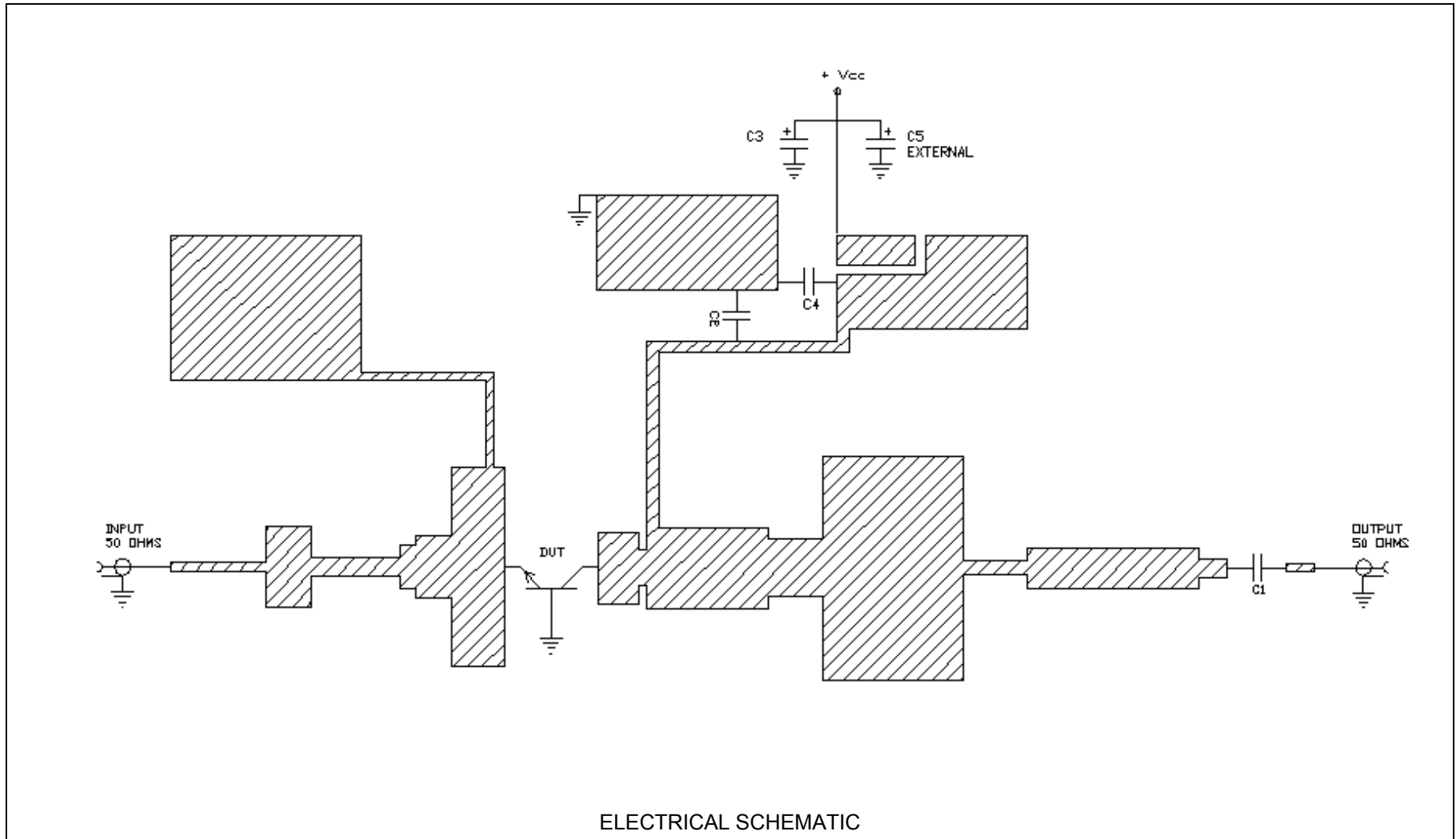


COMPONENT	DESCRIPTION
Q1	TRANSISTOR #IB1012S20, MOUNT HARD TO THE RIGHT
PC BOARD	ROGERS #R03010, TH=0.005" 1oz Cu
C1, C2	CHIP CAPACITOR, TYPE ATC1005, 100 pF
C3	ELECTROLYTIC CAPACITOR, 68uF / 63V
C4	CAPACITOR, TANTALUM, 4.7uF, 50V, low ESR=0.9ohms
C5 (NOT SHOWN)	STORAGE ELECTROLYTIC CAPACITOR, 4700uF / 30V
GS	GROUND SHIELD, COPPER, TH=0.001"
CONN1, CONN2	SMA CONNECTOR, TYPE DS #2052-5636-02
INPUT PC BOARD CARRIER	2 INCH BRASS - 03 (0.02)
OUTPUT PC BOARD CARRIER	2 INCH BRASS - 07 (0.2)
TRANSISTOR CARRIER	2 INCH COPPER - 01 (0.2)
TRANSISTOR CLAMP	NUTCL CLAMP - 01
ALUMINUM HEATSINK	2 INCH HEATSINK - 11
DC CONN1	BANANA JACK, BLACK
DC CONN2	BANANA JACK, RED

ASSEMBLY AND PARTS LIST

RF TEST FIXTURE





DEFINITIONS

Data Sheet Status	
Proposed Specification	This data sheet contains proposed specifications.
Preliminary Specification	This data sheet contains specifications based on preliminary measurements and data.
Product Specification	This data sheet contains final product specifications.
Maximum Ratings	
Stress above one or more of the maximum ratings may cause permanent damage to the device. These are maximum ratings only. Operation of the device at these or at any other conditions above those given in the characteristics sections of the specification is not implied. Exposure to maximum values for extended periods of time may affect device reliability.	

WARNING

Product and environmental safety - toxic materials
This product contains beryllium oxide. The product is entirely safe provided that the BeO base is not damaged. All persons who handle, use or dispose of this product should be aware of its nature and of the necessary safety precautions. After use, dispose of as chemical or special waste according to the regulations applying at the location of the user. It must never be thrown out with general or domestic waste.

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